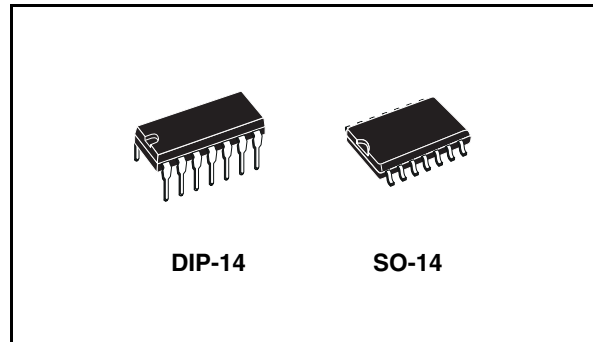


Quad 2-input and gate (open drain)

Features

- High Speed:
 $t_{PD} = 7\text{ns}$ (Typ.) at $V_{CC} = 6\text{V}$
- Low power dissipation:
 $I_{CC} = 1\mu\text{A}$ (Max.) at $T_A = 25^\circ\text{C}$
- High noise immunity:
 $V_{NIH} = V_{NIL} = 28\% V_{CC}$ (Min.)
- Balanced propagation delays:
 $t_{PLH} \approx t_{PHL}$
- Wide operating voltage range:
 V_{CC} (Opr) = 2V to 6V
- Pin and function compatible with 74 series 09



Description

The M74HC09 is an high speed CMOS Quad 2-input open drain and gate fabricated with silicon gate C²MOS technology.

The internal circuit is composed of 3 stages including buffer output, which enables high noise immunity and stable output.

All inputs are equipped with protection circuits against static discharge and transient excess voltage.

Order codes

Part number	Package	Packaging
M74HC09B1R	DIP-14	Tube
M74HC09M1R	SO-14	Tube
M74HC09RM13TR	SO-14	Tape and reel

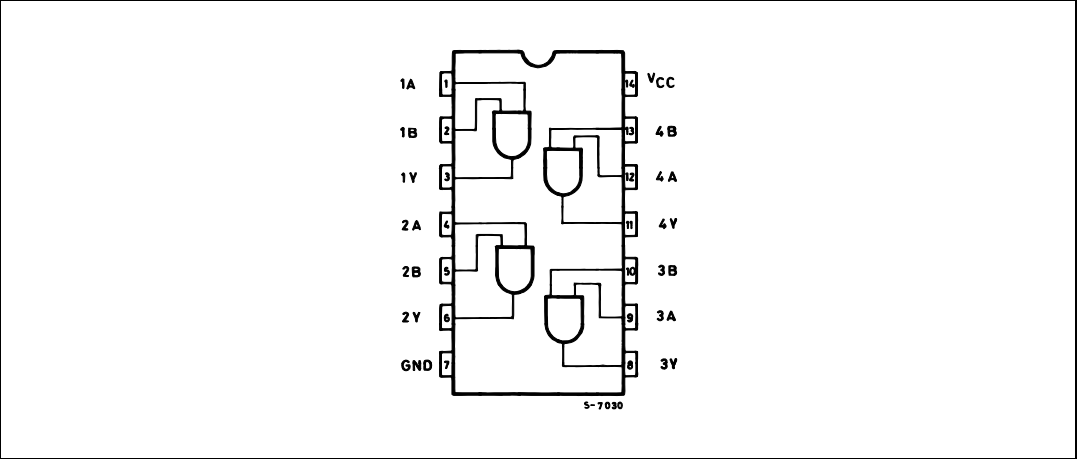
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1 Pin settings

1.1 Pin connection

Figure 1. Pin connection (top through view)



1.2 Pin description

Table 1. Pin description

Pin N°	Symbol	Name and function
1, 4, 9, 12	1A to 4A	Data Inputs
2, 5, 10, 13	1B to 4B	Data Inputs
3, 6, 8, 11	1Y to 4Y	Data Outputs
7	GND	Ground (0V)
14	V _{CC}	Positive Supply Voltage

2 Device summary

Figure 2. Input and output equivalent circuit

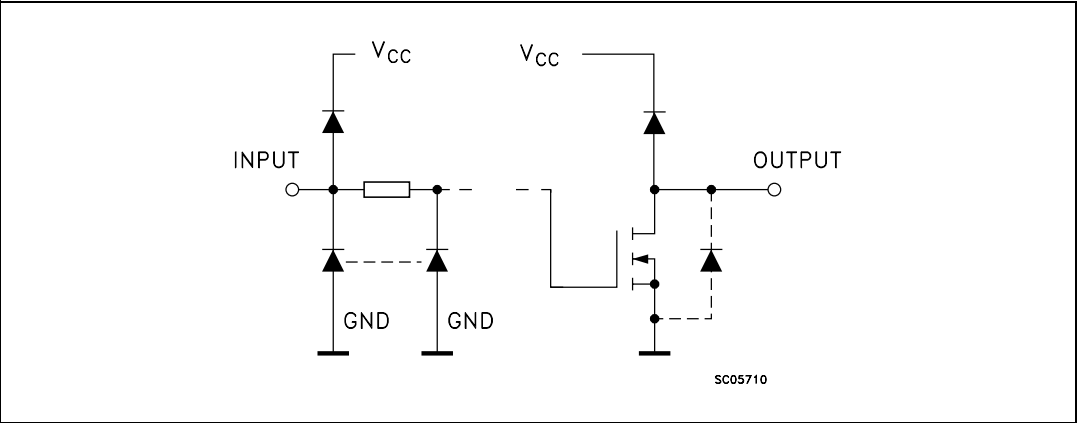


Figure 3. Logic diagram

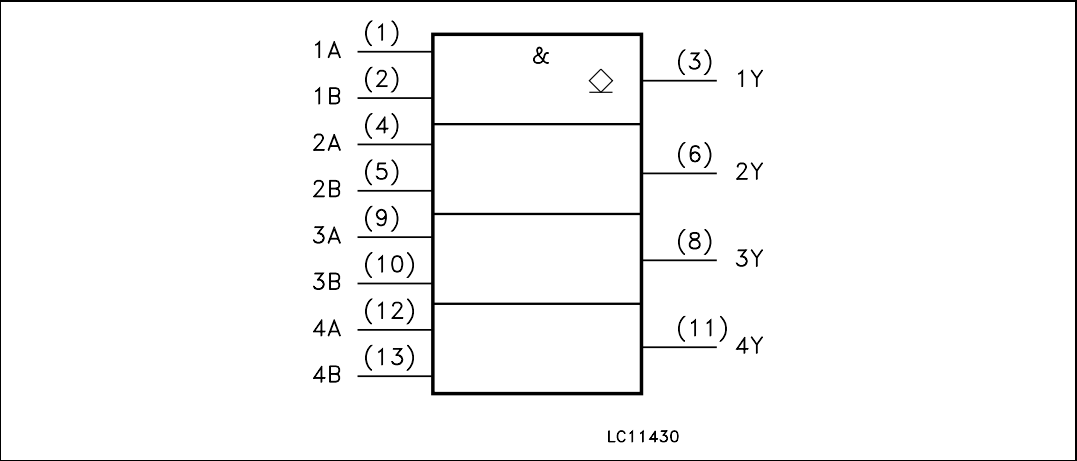


Table 2. Truth table

A	B	Y
L	L	L
L	H	L
H	L	L
H	H	Z

Note: Z : High Impedance

3 Maximum rating

Stressing the device above the rating listed in the “Absolute Maximum Ratings” table may cause permanent damage to the device. These are stress ratings only and operation of the device at these or any other conditions above those indicated in the Operating sections of this specification is not implied. Exposure to Absolute Maximum Rating conditions for extended periods may affect device reliability. Refer also to the STMicroelectronics SURE Program and other relevant quality documents.

Table 3. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{CC}	Supply Voltage	-0.5 to +7	V
V_I	DC Input Voltage	-0.5 to $V_{CC} + 0.5$	V
V_O	DC Output Voltage	-0.5 to $V_{CC} + 0.5$	V
I_{IK}	DC Input Diode Current	± 20	mA
I_{OK}	DC Output Diode Current	± 20	mA
I_O	DC Output Current	± 25	mA
I_{CC} or I_{GND}	DC V_{CC} or Ground Current	± 50	mA
P_D	Power Dissipation	500 ⁽¹⁾	mW
T_{stg}	Storage Temperature	-65 to +150	°C
T_L	Lead Temperature (10 sec)	300	°C

1. 500mW at 65 °C; derate to 300mW by 10mW/°C from 65°C to 85°C

3.1 Recommended operating conditions

Table 4. Recommended operating conditions

Symbol	Parameter		Value	Unit
V_{CC}	Supply Voltage		2 to 6	V
V_I	Input Voltage		0 to V_{CC}	V
V_O	Output Voltage		0 to V_{CC}	V
T_{op}	Operating Temperature		-55 to 125	°C
t_r, t_f	Input Rise and Fall Time	$V_{CC} = 2.0V$	0 to 1000	ns
		$V_{CC} = 4.5V$	0 to 500	ns
		$V_{CC} = 6.0V$	0 to 400	ns

4 Electrical characteristics

Table 5. DC specifications

Symbol	Parameter	Test condition		Value							Unit
		V _{CC} (V)		T _A = 25°C			-40 to 85°C		-55 to 125°C		
				Min	Typ	Max	Min	Max	Min	Max	
V _{IH}	High Level Input Voltage	2.0		1.5			1.5		1.5		V
		4.5		3.15			3.15		3.15		
		6.0		4.2			4.2		4.2		
V _{IL}	Low Level Input Voltage	2.0				0.5		0.5		0.5	V
		4.5				1.35		1.35		1.35	
		6.0				1.8		1.8		1.8	
V _{OL}	Low Level Output Voltage	2.0	I _O = 20μA		0.0	0.1		0.1		0.1	V
		4.5	I _O = 20μA		0.0	0.1		0.1		0.1	
		6.0	I _O = 20μA		0.0	0.1		0.1		0.1	
		4.5	I _O = 4.0mA		0.17	0.26		0.33		0.40	
		6.0	I _O = 5.2mA		0.18	0.26		0.33		0.40	
I _I	Input Leakage Current	6.0	V _I = V _{CC} or GND			±0.1		±1		±1	μA
I _{OZ}	Output Leakage Current	6.0	V _I = V _{IH} or V _{IL} V _O = V _{CC} or GND			±0.5		±5		±10	μA
I _{CC}	Quiescent Supply Current	6.0	V _I = V _{CC} or GND			1		10		20	μA

Table 6. AC electrical characteristics ($C_L = 50$ pF, Input $t_r = t_f = 6$ ns)

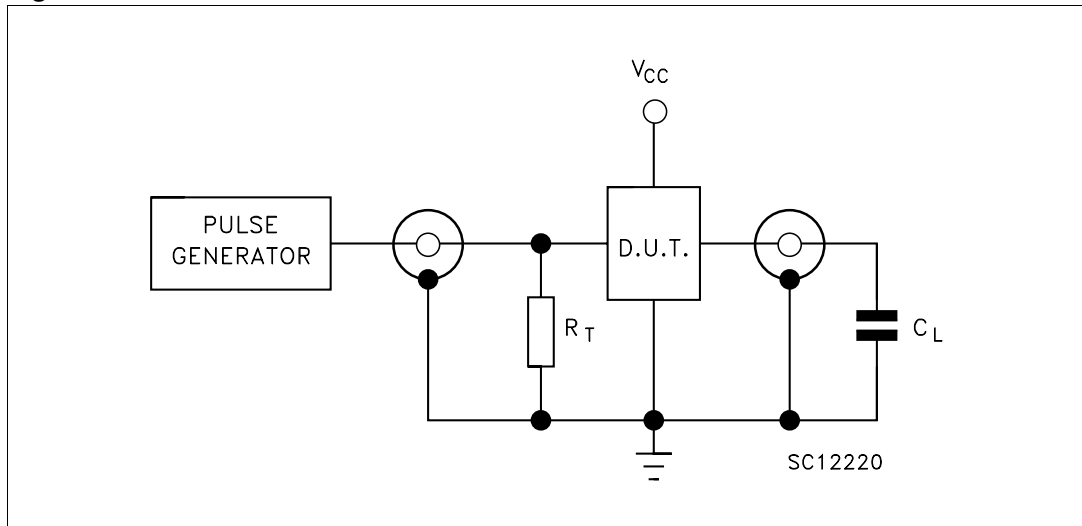
Symbol	Parameter	Test Condition		Value						Unit	
		V _{CC} (V)		T _A = 25°C			-40 to 85°C		-55 to 125°C		
				Min	Typ	Max	Min	Max	Min		Max
t _{THL}	Output Transition Time	2.0			30	75		95		110	ns
		4.5			8	15		19		22	
		6.0			7	13		16		19	
t _{PLZ}	Propagation Delay Time	2.0	R _L = 1 KΩ		10	75		95		110	ns
		4.5			8	15		19		22	
		6.0			7	13		16		19	
t _{PZL}	Propagation Delay Time	2.0	R _L = 1 KΩ		20	75		95		110	ns
		4.5			8	15		19		22	
		6.0			7	13		16		19	

Table 7. Capacitive characteristics

Symbol	Parameter	Test condition		Value							Unit
		V _{CC} (V)		T _A = 25°C			-40 to 85°C		-55 to 125°C		
				Min	Typ	Max	Min	Max	Min	Max	
C _{IN}	Input Capacitance	5.0			5	10		10		10	pF
C _{OUT}	Output Capacitance	5.0			10						pF
C _{PD}	Power Dissipation Capacitance (note 1)	5.0			6.5						pF

5 Test circuit

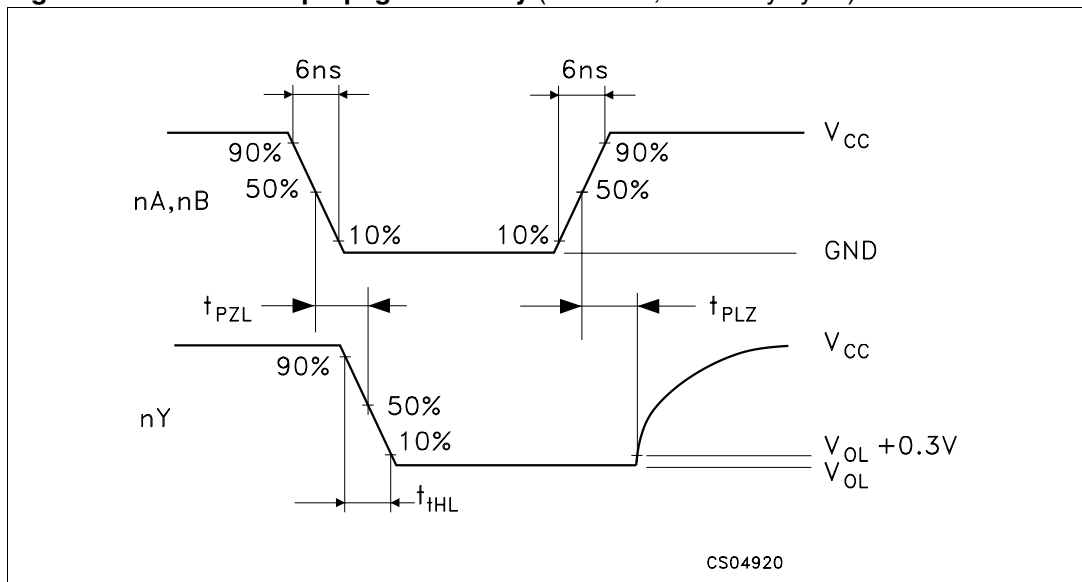
Figure 4. Test circuit



Note: $C_L = 50\text{pF}$ or equivalent (includes jig and probe capacitance)
 $R_T = Z_{OUT}$ of pulse generator (typically 50Ω)

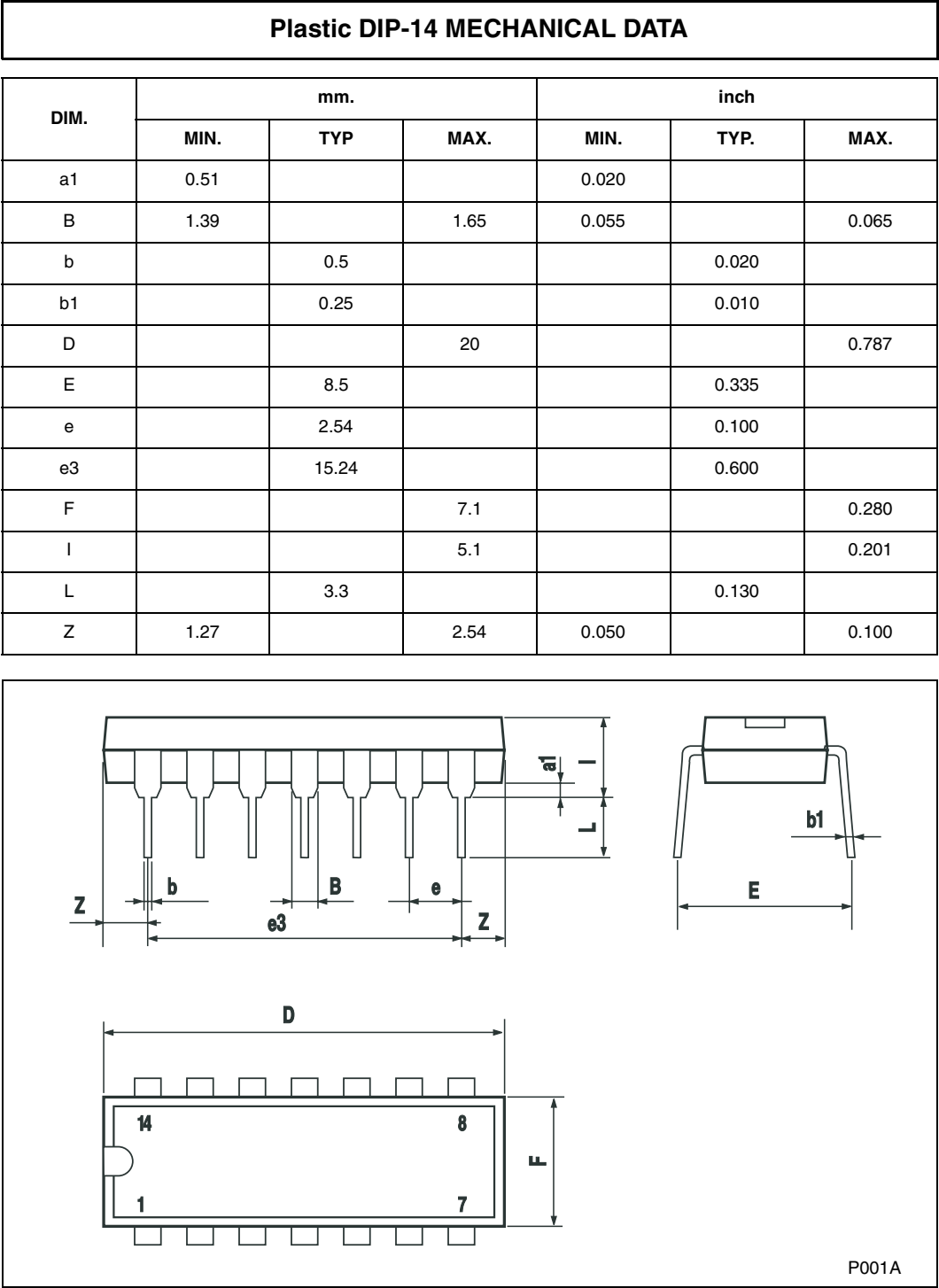
6 Waveforms

Figure 5. Waveform - propagation delay ($f = 1\text{MHz}$; 50% duty cycle)



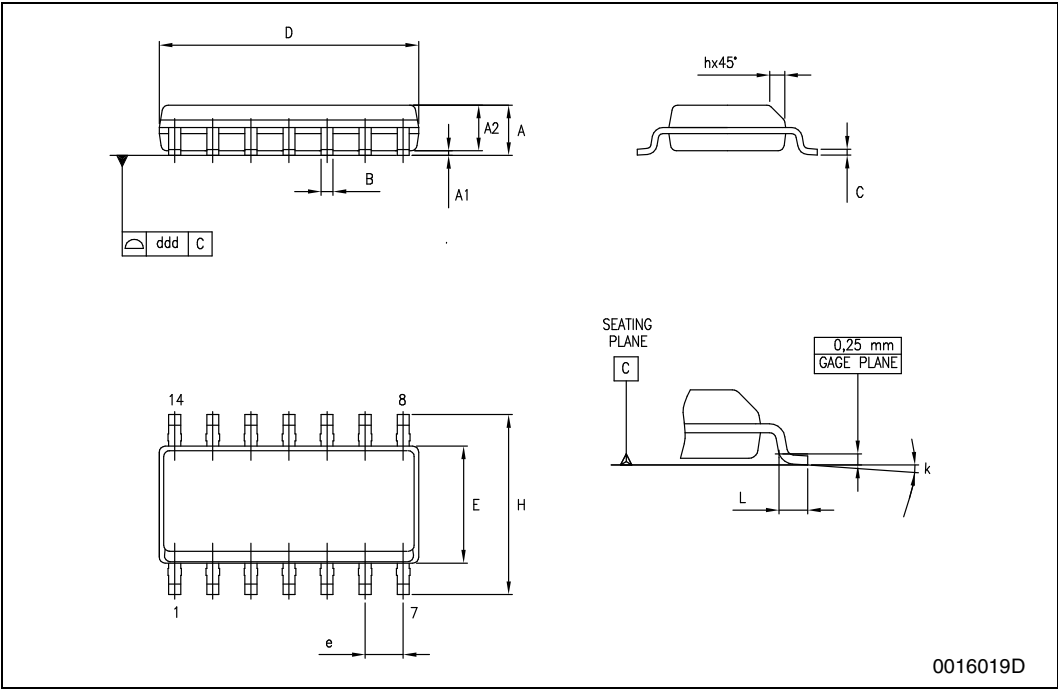
7 Package mechanical data

In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect . The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: www.st.com



SO-14 MECHANICAL DATA

DIM.	mm.			inch		
	MIN.	TYP	MAX.	MIN.	TYP.	MAX.
A	1.35		1.75	0.053		0.069
A1	0.1		0.25	0.004		0.010
A2	1.10		1.65	0.043		0.065
B	0.33		0.51	0.013		0.020
C	0.19		0.25	0.007		0.010
D	8.55		8.75	0.337		0.344
E	3.8		4.0	0.150		0.157
e		1.27			0.050	
H	5.8		6.2	0.228		0.244
h	0.25		0.50	0.010		0.020
L	0.4		1.27	0.016		0.050
k	0°		8°	0°		8°
ddd			0.100			0.004



0016019D

8 Revision history

Table 8. Revision history

Date	Revision	Changes
07-Aug-2001	1	First Release
19-May-2006	2	New template, deleted TSSOP14 package information

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